



CBR-SMD RF Auto COG, Ceramic, 0.3 pF, +/-0.1 pF, 50 VDC, COG, SMD, Fixed, RF, Ultra High Q, Low ESR, Class I, 0402



| Company | |
|--------------------------|---|
| General Information | |
| Series | CBR-SMD RF Auto COG |
| Style | SMD Chip |
| Description | SMD, Fixed, RF, Ultra High Q, Low ESR, Class I |
| Features | Ultra High Q, Low ESR, Class I |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| Qualifications | AEC-Q200 |
| AEC-Q200 | Yes |
| Halogen Free | Yes |
| Typical Component Weight | 1.37 mg |
| Notes | Solder Wave or Solder Reflow. |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|-----------------|
| Chip Size | 0402 |
| L | 1mm +/-0.05mm |
| W | 0.5mm +/-0.05mm |
| Т | 0.5mm +/-0.05mm |
| В | 0.25mm +/-0.1mm |

| Packaging Specifications | |
|--------------------------|--------------------------|
| Packaging | T&R, 180mm, Plastic Tape |
| Packaging Quantity | 10000 |

| Specifications | |
|--|------------------------|
| Capacitance | 0.3 pF |
| Tolerance | +/-0.1 pF |
| Voltage DC | 50 VDC |
| Dielectric Withstanding Voltage | 125 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | COG |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1MHz 1.0Vrms |
| Dissipation Factor | 0.25% 1 MHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour |
| Insulation Resistance | 10 GOhms |
| Quality Factor | 406 |

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